



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

0755-83047638

ysbdt@szyoushang.cn

www.szyoushang.cn



企业微信二维码



企业QQ二维码

Product Summary

$V_{(BR)DSS}$	$R_{DS(ON)}$ Max	I_D Max $T_c = +25^\circ\text{C}$
-60V	105m Ω @ $V_{GS} = -10V$	-7.3A
	130m Ω @ $V_{GS} = -4.5V$	-6.5A

Features and Benefits

- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed

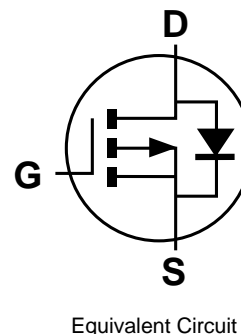
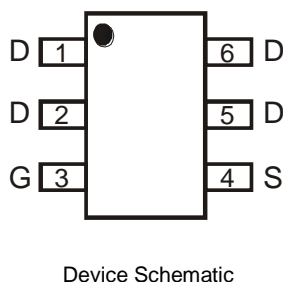
Description and Applications

This MOSFET is designed to minimize the on-state resistance ($R_{DS(ON)}$) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

- Backlighting
- Power Management Functions
- DC-DC Converters

Mechanical Data

- Case: TSOT26
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections Indicator: See Diagram
- Terminals: Finish — Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 **e3**
- Weight: 0.008 grams (Approximate)



Maximum Ratings (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Drain-Source Voltage	V_{DSS}	-60	V	
Gate-Source Voltage	V_{GSS}	± 20	V	
Continuous Drain Current (Note 6) $V_{GS} = -10\text{V}$	I_D	$T_C = +25^\circ\text{C}$	-7.3	A
		$T_C = +70^\circ\text{C}$	-5.8	A
Maximum Body Diode Forward Current (Note 6)	I_S	-1.8	A	
Pulsed Drain Current (380 μs Pulse, 1% Duty Cycle)	I_{DM}	-24	A	
Avalanche Current (Note 7) $L = 0.1\text{mH}$	I_{AS}	-19	A	
Repetitive Avalanche Energy (Note 7) $L = 0.1\text{mH}$	E_{AS}	18	mJ	

Thermal Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Total Power Dissipation (Note 5)	P_D	$T_A = +25^\circ\text{C}$	1.2	W
		$T_A = +70^\circ\text{C}$	0.75	
Thermal Resistance, Junction to Ambient (Note 5)	$R_{\theta JA}$	Steady state	105	$^\circ\text{C/W}$
		$t < 10\text{s}$	60	$^\circ\text{C/W}$
Total Power Dissipation (Note 6)	P_D	$T_A = +25^\circ\text{C}$	1.8	W
		$T_A = +70^\circ\text{C}$	1.1	
Thermal Resistance, Junction to Ambient (Note 6)	$R_{\theta JA}$	Steady state	69	$^\circ\text{C/W}$
		$t < 10\text{s}$	39	$^\circ\text{C/W}$
Thermal Resistance, Junction to Case (Note 6)	$R_{\theta JC}$	15	$^\circ\text{C/W}$	
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ\text{C}$	

Electrical Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV_{DSS}	-60	—	—	V	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	-1	μA	$V_{DS} = -48\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	—	—	100	nA	$V_{GS} = \pm 16\text{V}, V_{DS} = 0\text{V}$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	$V_{GS(TH)}$	-1	—	-3	V	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	—	105	m Ω	$V_{GS} = -10\text{V}, I_D = -4.5\text{A}$
		—	—	130		$V_{GS} = -4.5\text{V}, I_D = -3.5\text{A}$
Diode Forward Voltage	V_{SD}	—	-0.7	-1.2	V	$V_{GS} = 0\text{V}, I_S = -1\text{A}$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C_{ISS}	—	969	—	pF	$V_{DS} = -30\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	C_{OSS}	—	57	—		
Reverse Transfer Capacitance	C_{RSS}	—	44	—		
Gate Resistance	R_G	—	13.7	—	Ω	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Total Gate Charge ($V_{GS} = -4.5\text{V}$)	Q_g	—	8.2	—	nC	$V_{DS} = -30\text{V}, I_D = -12\text{A}$
Total Gate Charge ($V_{GS} = -10\text{V}$)	Q_g	—	17.2	—		
Gate-Source Charge	Q_{gs}	—	3.0	—		
Gate-Drain Charge	Q_{gd}	—	3.1	—		
Turn-On Delay Time	$t_{D(ON)}$	—	4.4	—	ns	$V_{GS} = -10\text{V}, V_{DS} = -30\text{V}, R_{GEN} = 3\Omega, I_D = -12\text{A}$
Turn-On Rise Time	t_R	—	23	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	34	—		
Turn-Off Fall Time	t_F	—	42	—		
Body Diode Reverse Recovery Time	t_{RR}	—	13.2	—	ns	$I_S = -12\text{A}, dI/dt = 100\text{A}/\mu\text{s}$
Body Diode Reverse Recovery Charge	Q_{RR}	—	6.18	—	nC	

- Notes:
- Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
 - Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
 - I_{AS} and E_{AS} rating are based on low frequency and duty cycles to keep $T_J = +25^\circ\text{C}$.
 - Short duration pulse test used to minimize self-heating effect.
 - Guaranteed by design. Not subject to product testing.

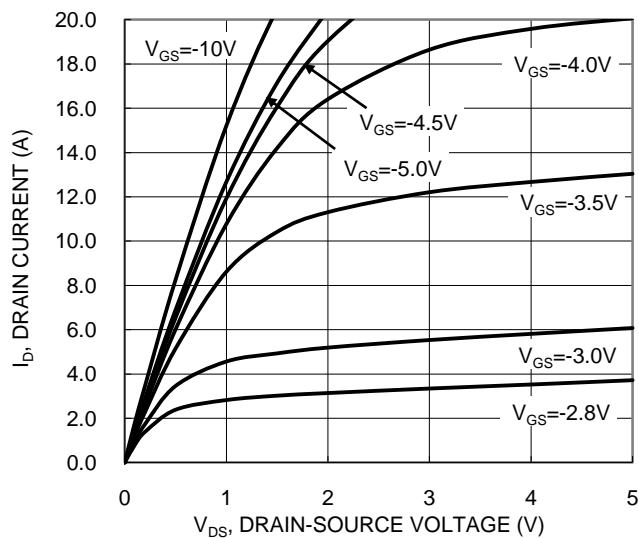


Figure 1. Typical Output Characteristic

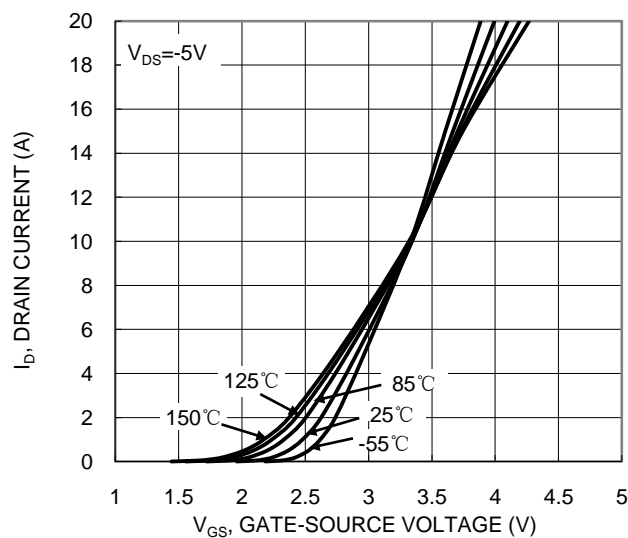


Figure 2. Typical Transfer Characteristic

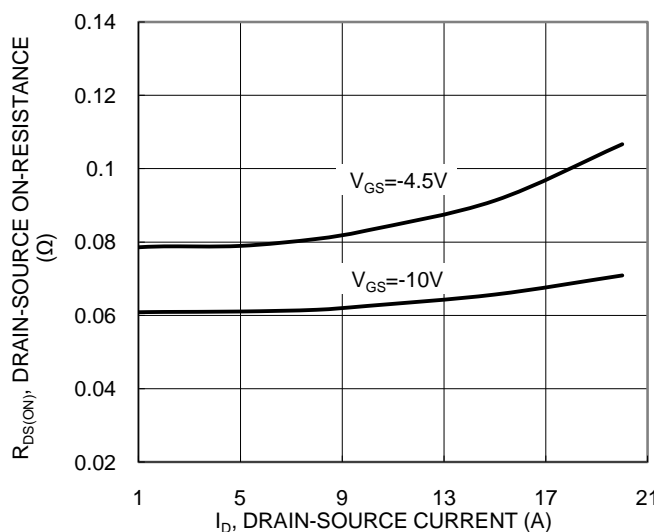


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

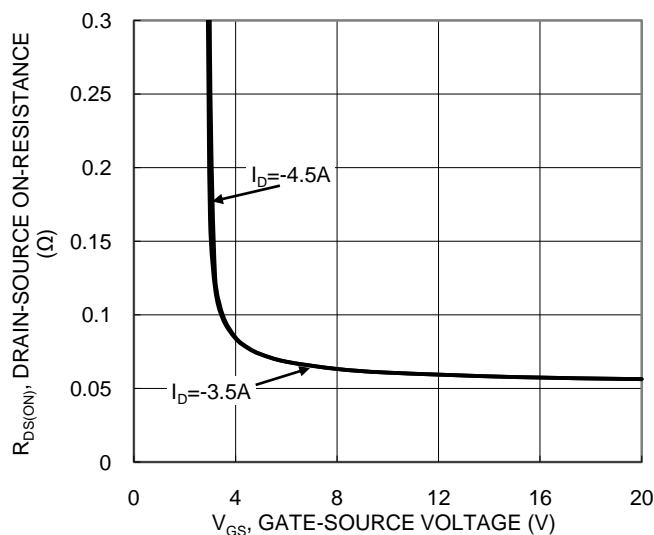


Figure 4. Typical Transfer Characteristic

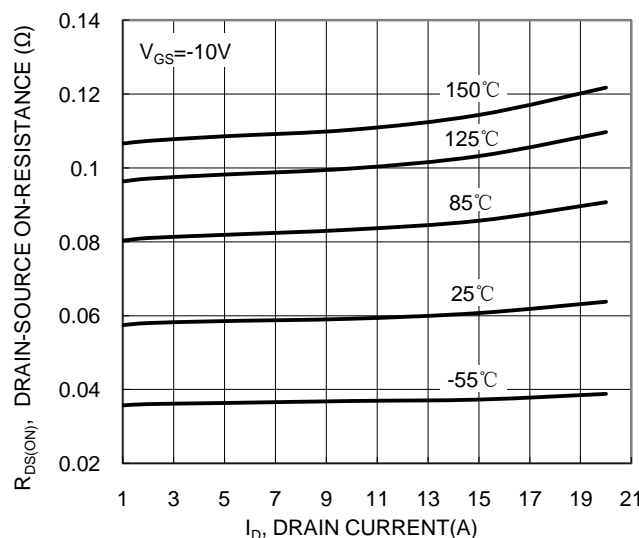


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

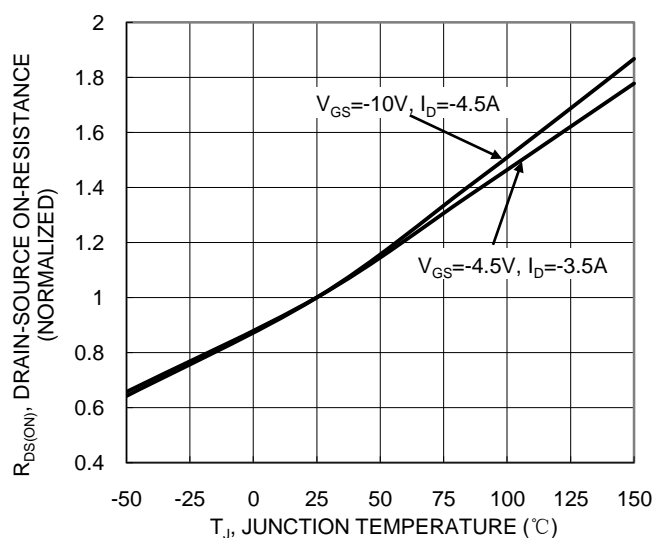


Figure 6. On-Resistance Variation with Temperature

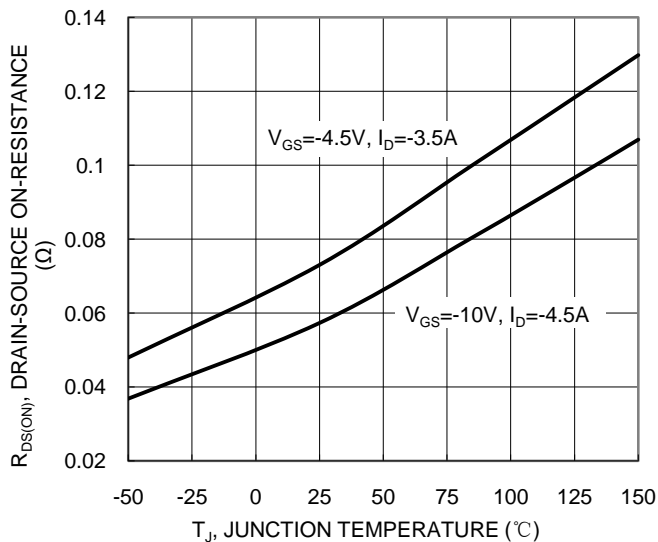


Figure 7. On-Resistance Variation with Temperature

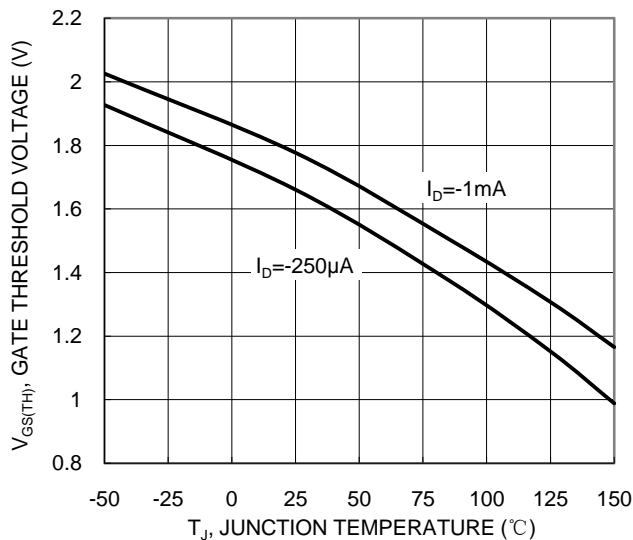


Figure 8. Gate Threshold Variation vs. Junction Temperature

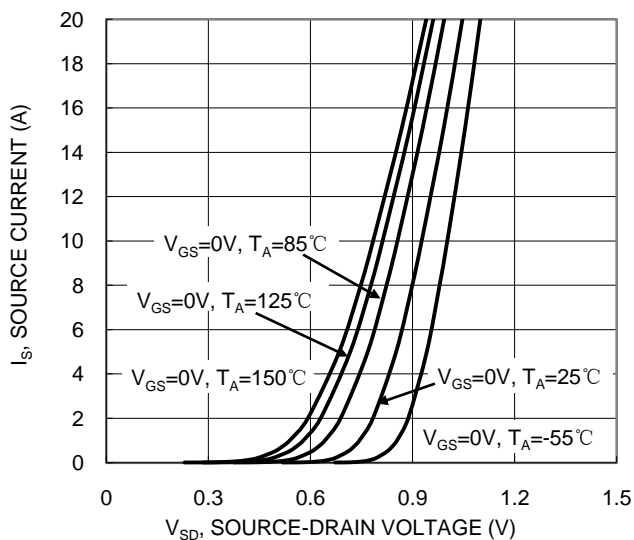


Figure 9. Diode Forward Voltage vs. Current

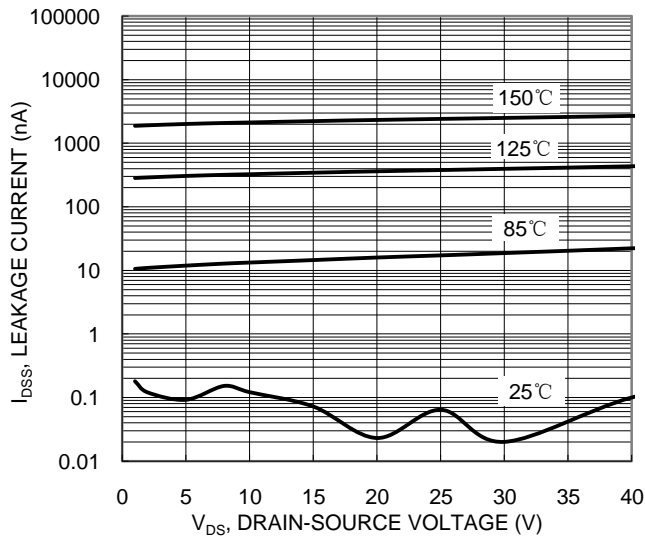


Figure 10. Typical Drain-Source Leakage Current vs. Voltage

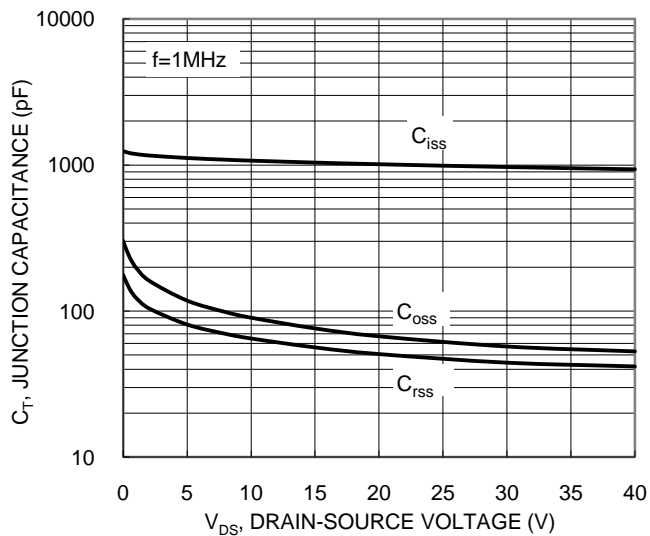


Figure 11. Typical Junction Capacitance

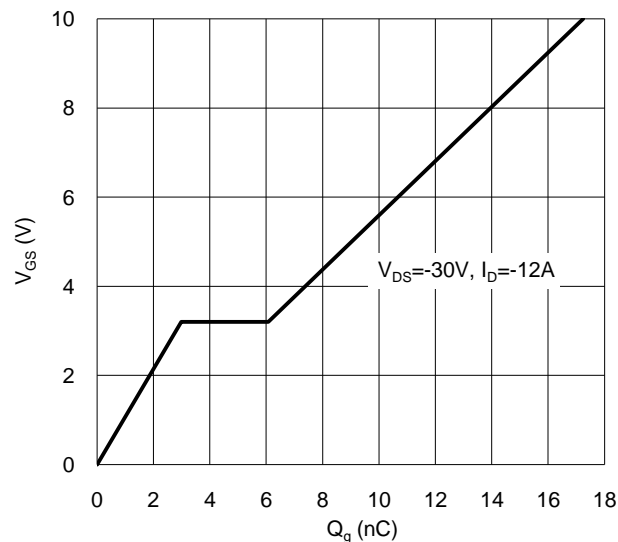
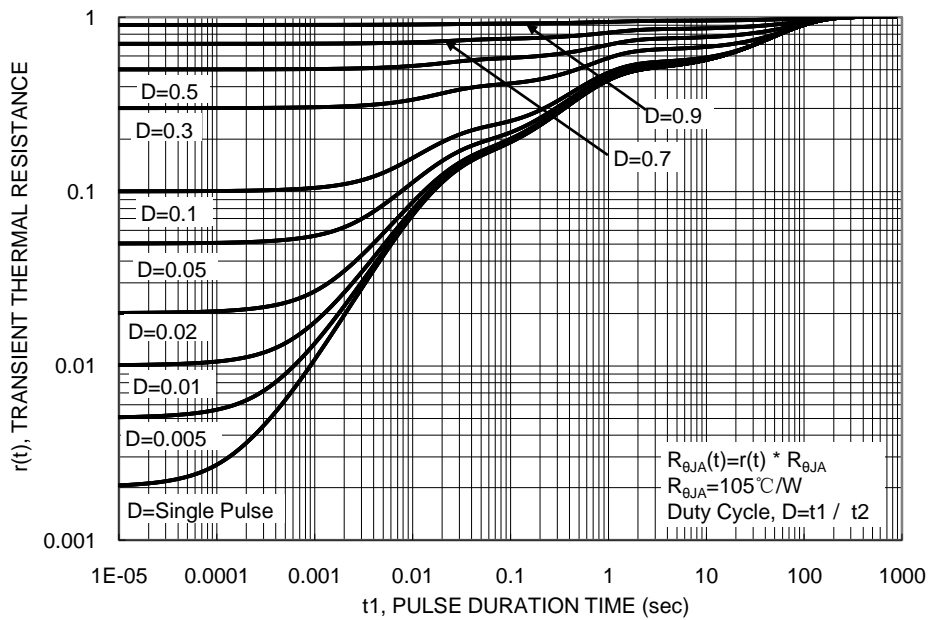
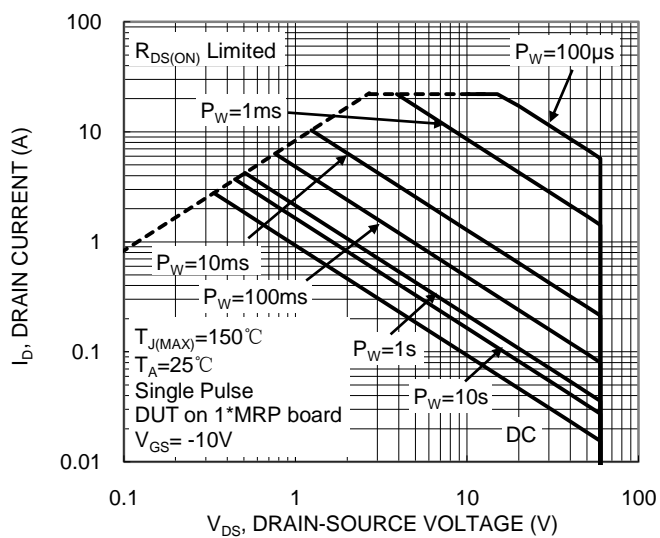
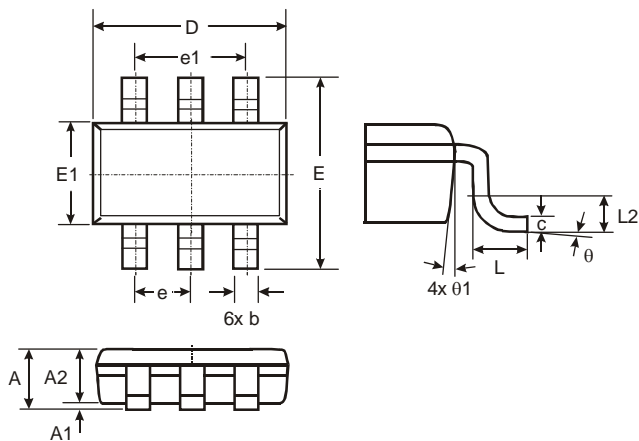


Figure 12. Gate Charge

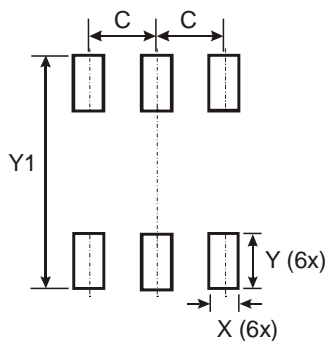


Package Outline Dimensions



TSOT26			
Dim	Min	Max	Typ
A	-	1.00	-
A1	0.01	0.10	-
A2	0.84	0.90	-
D	-	-	2.90
E	-	-	2.80
E1	-	-	1.60
b	0.30	0.45	-
c	0.12	0.20	-
e	-	-	0.95
e1	-	-	1.90
L	0.30	0.50	-
L2	-	-	0.25
theta	0°	8°	4°
theta1	4°	12°	-
All Dimensions in mm			

Suggested Pad Layout



Dimensions	Value (in mm)
C	0.950
X	0.700
Y	1.000
Y1	3.199